

ABSTRACT

A method of verifying test data for testing an integrated circuit device having multiple device time domains includes selecting a virtual tester time domain and, if the cycle duration of the virtual tester time domain is equal to the cycle duration of one of the multiple device time domains, translating the test data for each device time domain other than that one time domain to the virtual tester time domain and otherwise translating the test data for each device time domain to the virtual tester time domain. The translated test data is then applied to a device logic simulator that simulates the integrated circuit device.